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Supplemental Material: Impact of proton-induced transmutation doping in semiconductors for space applications

## 1 Experimental Data Processing

The linear calibration function and detector efficiency calibration function for the Canberra Industries Genie-2000 Spectroscopy System High Purity Ge Detector are shown in Fig. 1 and Fig. 2 respectively.<sup>9</sup>

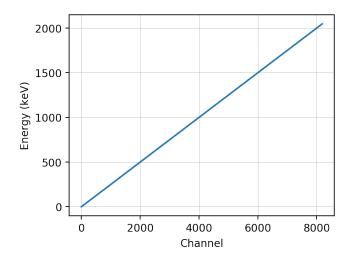


Fig. 1 Channel-to-energy calibration function for the HPGe detector system used in this work to quantify transmutation of an irradiated GaAs sample.

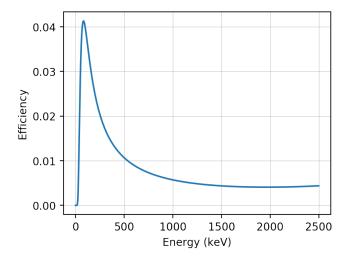
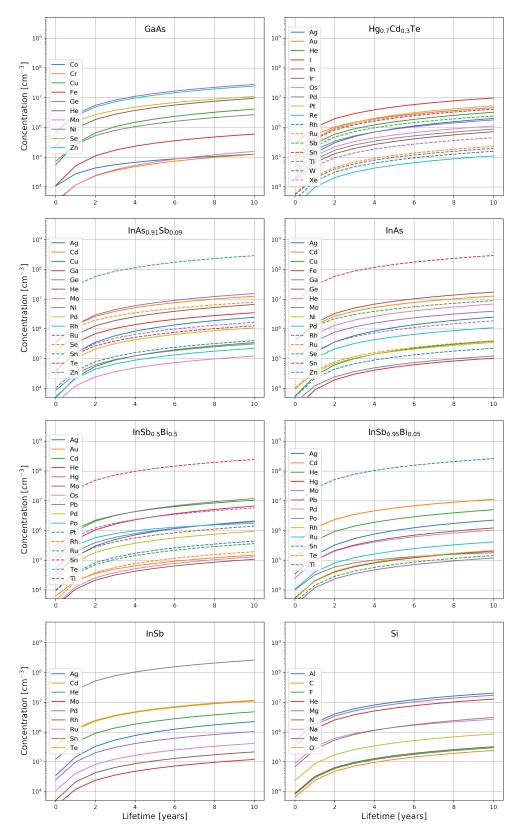


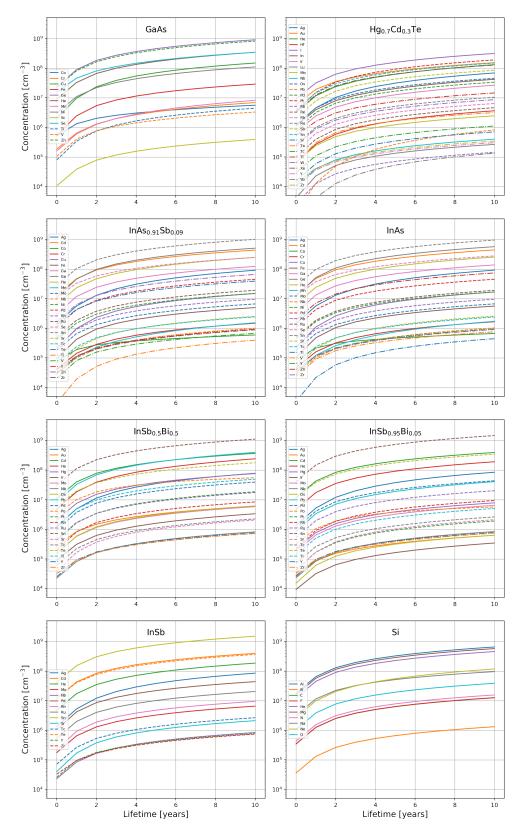
Fig. 2 Efficiency function for the HPGe detector system used in this work to quantify transmutation of an irradiated GaAs sample. This includes detector and geometrical efficiency.

## 2 Orbit Dominant Temporal Impurity Concentrations

This section contains the impurity concentrations for inclined nonpolar low earth orbit (LEO), polar sun-synchronous LEO, semisynchronous medium earth orbit (MEO), and geostationary orbit (GEO) for GaAs, Hg<sub>0.7</sub>Cd<sub>0.3</sub>Te, InAs<sub>0.91</sub>Sb<sub>0.09</sub>, InAs, InSb<sub>0.5</sub>Bi<sub>0.5</sub>, InSb<sub>0.95</sub>Bi<sub>0.05</sub>, InSb and Si over the course of 10 years of operation.



**Fig. 3** Impurity concentration ( $cm^{-3}$ ) for elements with concentrations in excess of  $> 10^5 cm^{-3}$  for GaAs, Hg<sub>0.7</sub>Cd<sub>0.3</sub>Te, InAs<sub>0.91</sub>Sb<sub>0.09</sub>, InAs, InSb<sub>0.5</sub>Bi<sub>0.5</sub>, InSb<sub>0.95</sub>Bi<sub>0.05</sub>, InSb and Si as a function of lifetime in inclined nonpolar LEO.



**Fig. 4** Impurity concentration ( $cm^{-3}$ ) for elements with concentrations in excess of  $> 10^5 cm^{-3}$  for GaAs,  $Hg_{0.7}Cd_{0.3}$ Te,  $InAs_{0.91}Sb_{0.09}$ , InAs,  $InSb_{0.5}Bi_{0.5}$ ,  $InSb_{0.95}Bi_{0.05}$ , InSb and Si as a function of lifetime in polar sun-synchronous LEO.

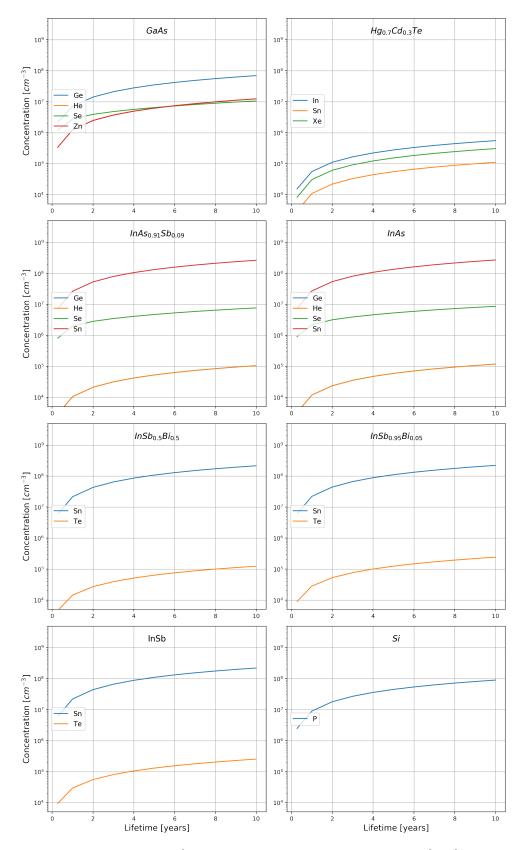


Fig. 5 Impurity concentration ( $cm^{-3}$ ) for elements with concentrations in excess of  $> 10^5 cm^{-3}$  for GaAs, Hg<sub>0.7</sub>Cd<sub>0.3</sub>Te, InAs<sub>0.91</sub>Sb<sub>0.09</sub>, InAs, InSb<sub>0.5</sub>Bi<sub>0.5</sub>, InSb<sub>0.95</sub>Bi<sub>0.05</sub>, InSb and Si as a function of lifetime in MEO.

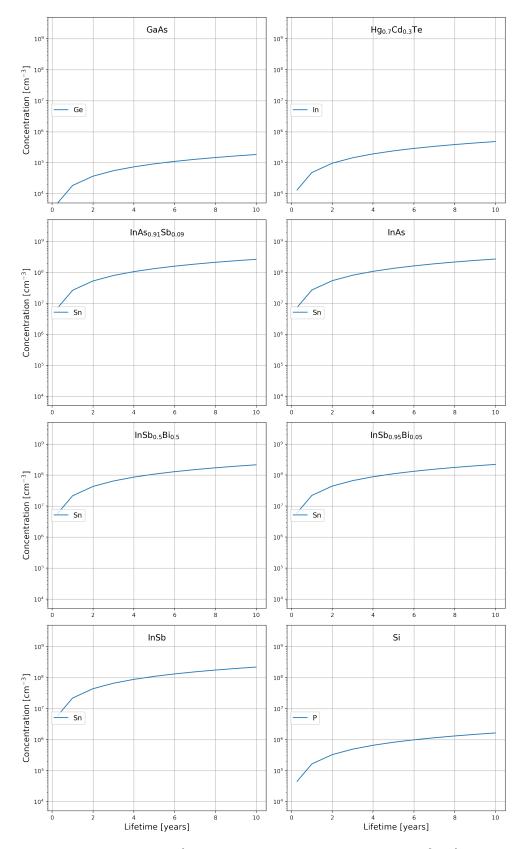


Fig. 6 Impurity concentration ( $cm^{-3}$ ) for elements with concentrations in excess of  $> 10^5 cm^{-3}$  for GaAs, Hg<sub>0.7</sub>Cd<sub>0.3</sub>Te, InAs<sub>0.91</sub>Sb<sub>0.09</sub>, InAs, InSb<sub>0.5</sub>Bi<sub>0.5</sub>, InSb<sub>0.95</sub>Bi<sub>0.05</sub>, InSb and Si as a function of lifetime in GEO.